



# FCB11N60F 600V N-Channel MOSFET

# Features

- 650V @T<sub>J</sub> = 150°C
- Typ. R<sub>DS(on)</sub> = 0.32Ω
- Fast Recovery Type ( t<sub>rr</sub> = 120ns )
- Ultra low gate charge (typ.  $Q_g = 40nC$ )
- Low effective output capacitance (typ.  $C_{oss}$ .eff = 95pF)
- 100% avalanche tested
- RoHS Compliant



D

D<sup>2</sup>-PAK

FCB Series

G S

# Description

SuperFET<sup>TM</sup> is, Fairchild's proprietary, new generation of high voltage MOSFET family that is utilizing an advanced charge balance mechanism for outstanding low on-resistance and lower gate charge performance.

This advanced technology has been tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. Consequently, SuperFET is very suitable for various AC/DC power conversion in switching mode operation for system miniaturization and higher efficiency.

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# **Absolute Maximum Ratings**

Symbol	I Parameter Drain-Source Voltage		FCB11N60F	Unit V	
V <sub>DSS</sub>			600		
Ι <sub>D</sub>	Drain Current - Continuous - Continuous	$(T_{C} = 25^{\circ}C)$ $(T_{C} = 100^{\circ}C)$	11 7	A A	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	33	A	
V <sub>GSS</sub>	Gate-Source voltage		$\pm 30$	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	340	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	11	А	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	12.5	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	50	V/ns	
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C) - Derate above 25°C		125 1.0	W W/°C	
T <sub>J,</sub> T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	°C	

# **Thermal Characteristics**

Symbol	Parameter	FCB11N60F	Unit	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.0	°C/W	
$R_{\theta JA}^{*}$	Thermal Resistance, Junction-to-Ambient*	40	°C/W	
$R_{\thetaJA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W	
When mounted on	the minimum pad size recommended (PCB Mount)			

Device Marking		Device	Packa	•		24m		Quantity 800	
FCB1	•		D <sup>2</sup> -PAł						
Electric	cal Cha	racteristics T <sub>c</sub> =	25°C unless oth	erwise noted					
Symbo	I	Parameter		Condition	S	Min	Тур	Max	Units
Off Chara	cteristics								
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage		e V <sub>G</sub>	$V_{GS} = 0V, I_D = 250 \mu A, T_J = 25^{\circ}C$		600			V
			V <sub>G</sub>	$V_{GS} = 0V, I_D = 250 \mu A, T_J = 150^{\circ}C$			650		V
$\Delta BV_{DSS}$ / $\Delta T_{J}$	Breakdow Coefficier	eakdown Voltage Temperature efficient		$I_D = 250 \mu A$ , Referenced to 25°C			0.6		V/°C
BV <sub>DS</sub>	Drain-Sou Voltage	rain-Source Avalanche Breakdown oltage		V <sub>GS</sub> = 0V, I <sub>D</sub> = 11A			700		V
I <sub>DSS</sub>	Zero Gate	Zero Gate Voltage Drain Current		$V_{DS} = 600V, V_{GS} = 0V$ $V_{DS} = 480V, T_{C} = 125^{\circ}C$				10 100	μΑ μΑ
I <sub>GSSF</sub>	Gate-Bod	y Leakage Current, For	ward V <sub>G</sub>	$V_{GS} = 30V, V_{DS} = 0V$				100	nA
I <sub>GSSR</sub>	Gate-Bod	y Leakage Current, Rev	verse V <sub>G</sub>	$V_{GS} = -30V, V_{DS} = 0V$				-100	nA
On Chara	cteristics								
V <sub>GS(th)</sub>	Gate Thre	Gate Threshold Voltage		$V_{DS} = V_{GS}, I_D = 250 \mu A$		3.0		5.0	V
R <sub>DS(on)</sub>		Static Drain-Source On-Resistance		<sub>S</sub> = 10V, I <sub>D</sub> = 5.5A			0.32	0.38	Ω
9fs	Forward 7	Transconductance		<sub>S</sub> = 40V, I <sub>D</sub> = 5.5A	(Note 4)		9.7		S
Dynamic	Characteris	tics						•	<u>.</u>
C <sub>iss</sub>	Input Cap	acitance		$V_{DS} = 25V, V_{GS} = 0V,$ f = 1.0MHz			1148	1490	pF
C <sub>oss</sub>	Output Ca	apacitance	f =				671	870	pF
C <sub>rss</sub>	Reverse <sup>-</sup>	Transfer Capacitance					63		pF
C <sub>oss</sub>	Output Ca	Output Capacitance		$V_{DS} = 480V, V_{GS} = 0V, f = 1.0MHz$			35		pF
C <sub>oss</sub> eff.	Effective	ffective Output Capacitance		$V_{\rm DS}$ = 0V to 400V, $V_{\rm GS}$ = 0V			95		pF
Switching	Characteri	istics						•	<u>.</u>
t <sub>d(on)</sub>	Turn-On I	Delay Time		$V_{DD} = 300V, I_D = 11A$ $R_G = 25\Omega$			34	80	ns
t <sub>r</sub>	Turn-On I	Rise Time	R <sub>G</sub>				98	205	ns
t <sub>d(off)</sub>	Turn-Off I	Delay Time					119	250	ns
t <sub>f</sub>	Turn-Off I	all Time			(Note 4, 5)		56	120	ns
Qg	Total Gate	e Charge	V <sub>D</sub>	$V_{DS} = 480V, I_{D} = 11A$ $V_{GS} = 10V$ (Note 4, 5)			40	52	nC
Q <sub>gs</sub>	Gate-Sou	rce Charge	V <sub>G</sub>				7.2		nC
Q <sub>gd</sub>	Gate-Dra	in Charge					21		nC
Drain-Sou	Irce Diode (	Characteristics and Ma	aximum Ra	tings					
I <sub>S</sub>	Maximum	Maximum Continuous Drain-Source Diod		de Forward Current				11	Α
I <sub>SM</sub>	Maximum	Maximum Pulsed Drain-Source Diode Fo		orward Current				33	Α
V <sub>SD</sub>	Drain-Sou	urce Diode Forward Vol	tage V <sub>G</sub>	<sub>S</sub> = 0V, I <sub>S</sub> = 11A				1.4	V
t <sub>rr</sub>	Reverse I	Recovery Time		<sub>S</sub> = 0V, I <sub>S</sub> = 11A			120		ns
Q <sub>rr</sub>	Reverse I	Recovery Charge	dl <sub>F</sub>	$dI_F/dt = 100A/\mu s$ (Note 4)			0.8		μC

1. Repetitive Rating: Pulse width limited by maximum junction temperature

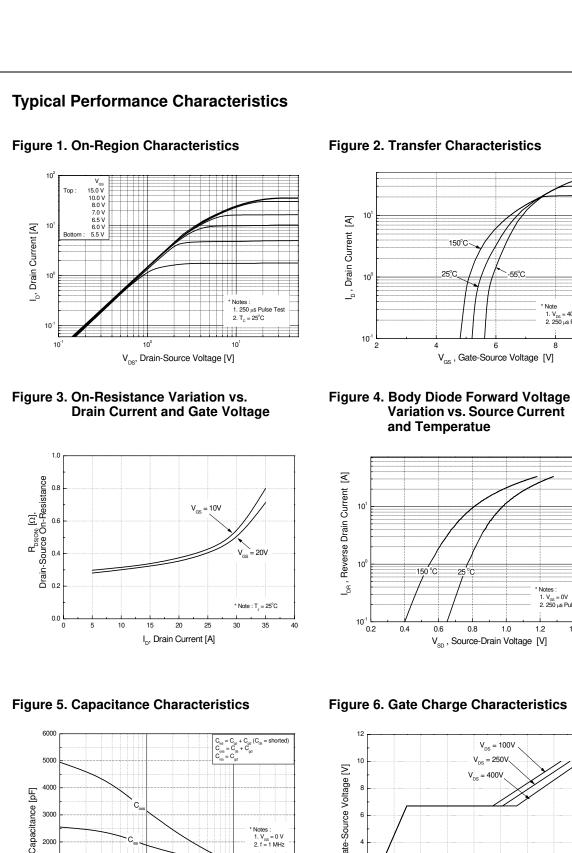
2.  $I_{AS}$  = 5.5A,  $V_{DD}$  = 50V,  $R_{G}$  = 25 $\Omega$ , Starting  $T_{J}$  = 25 $^{\circ}C$ 

3.  $I_{SD} \leq$  11A, di/dt  $\leq$  1200A/µs,  $V_{DD} \leq BV_{DSS},$  Starting  $T_J$  = 25°C

4. Pulse Test: Pulse width  $\leq 300 \mu s,$  Duty Cycle  $\leq 2\%$ 

5. Essentially Independent of Operating Temperature Typical Characteristics

2



## **Figure 2. Transfer Characteristics**

-55°C

6

Note 1. V<sub>DS</sub> = 40V 2. 250 μs Pulse Test

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Notes : 1. V... = 0V 2. 250 μs Pulse Te

1.2

1.4

1.6

1.0

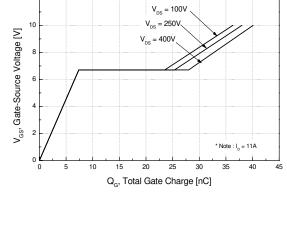
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V<sub>DS</sub>, Drain-Source Voltage [V]

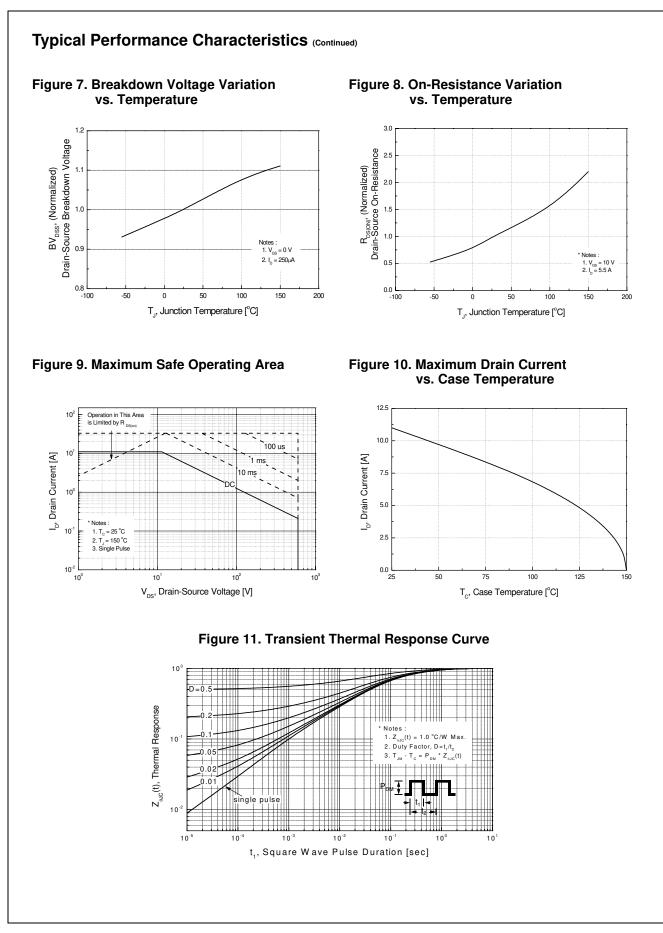
10

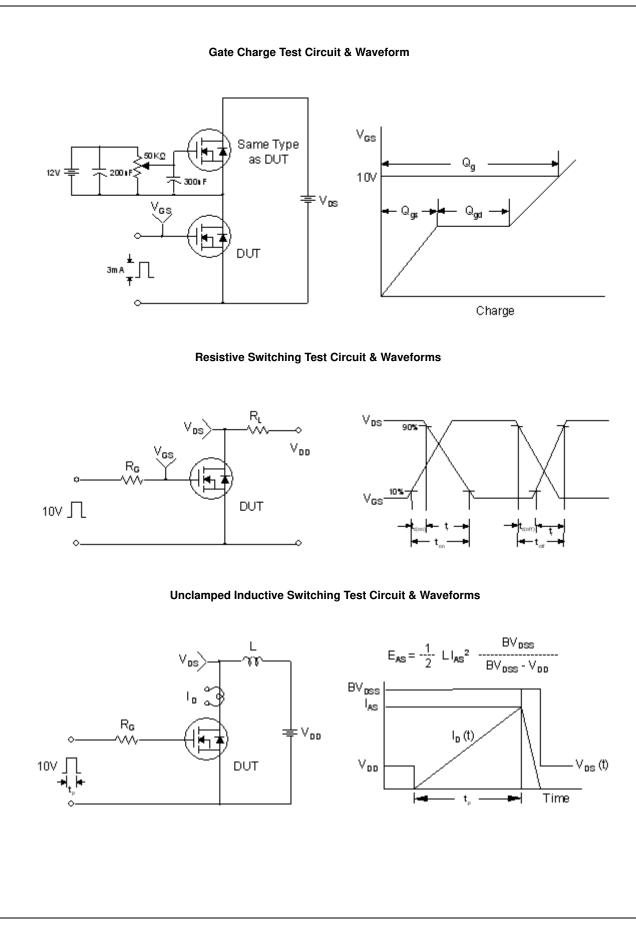




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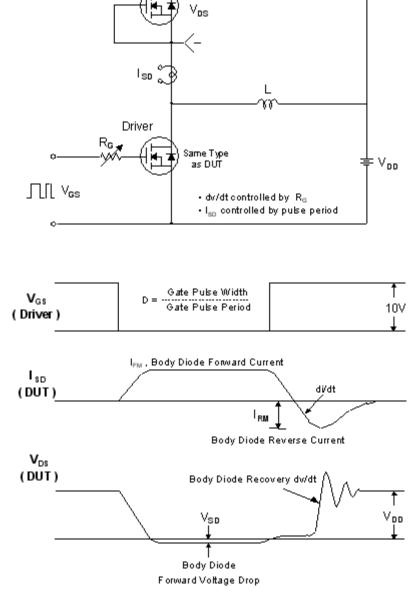
0 L 10<sup>-1</sup>

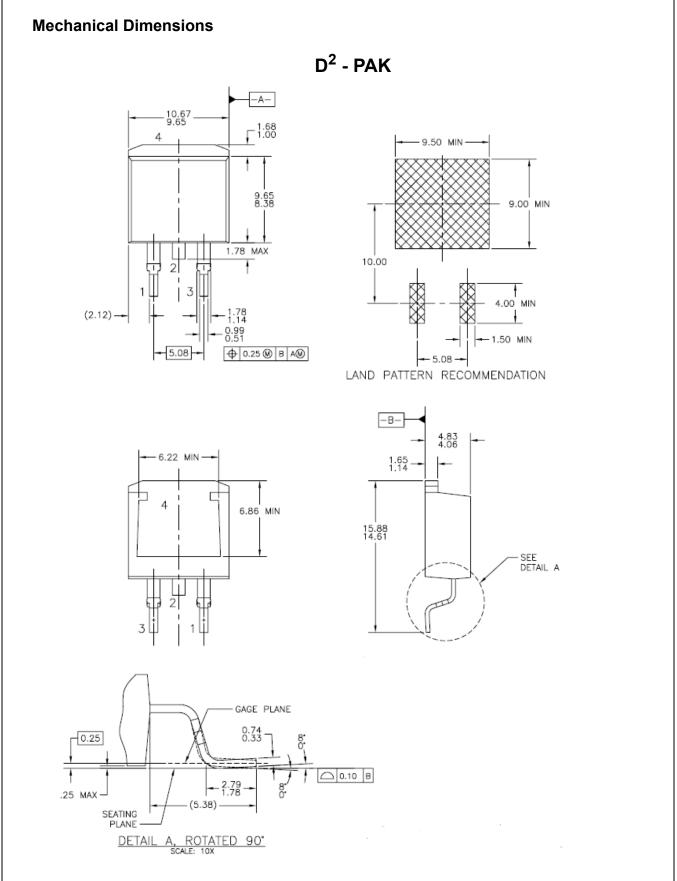


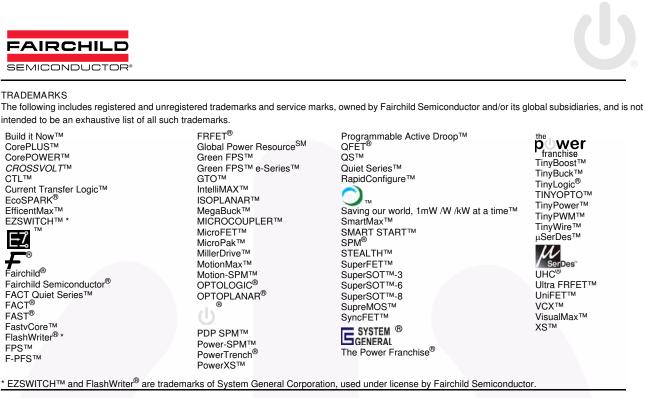


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# Peak Diode Recovery dv/dt Test Circuit & Waveforms







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